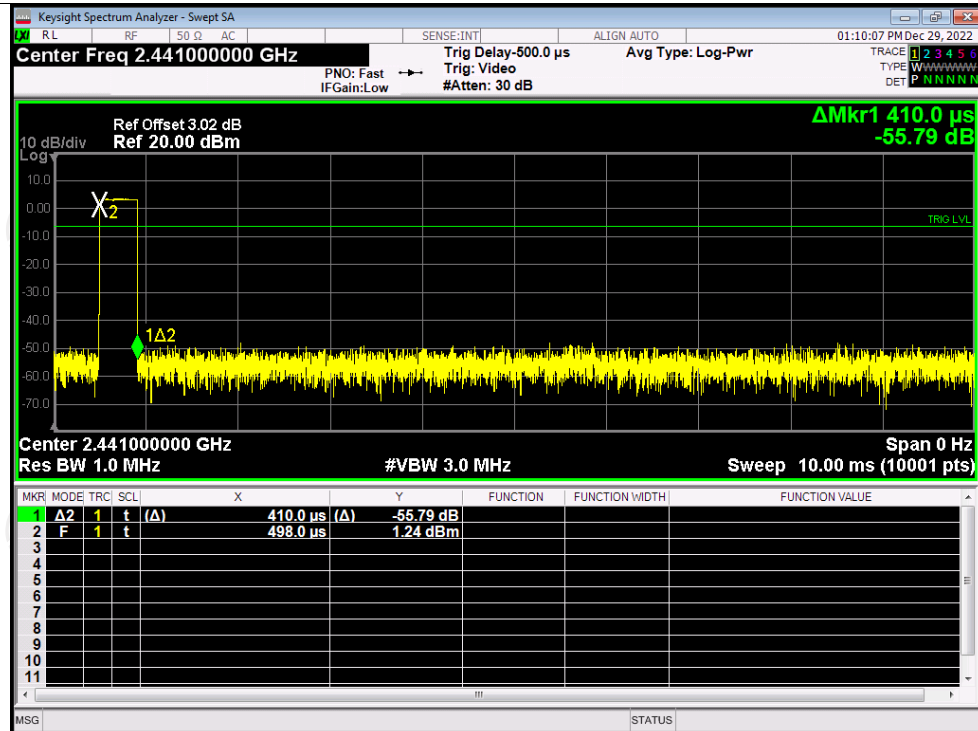


Dwell Time

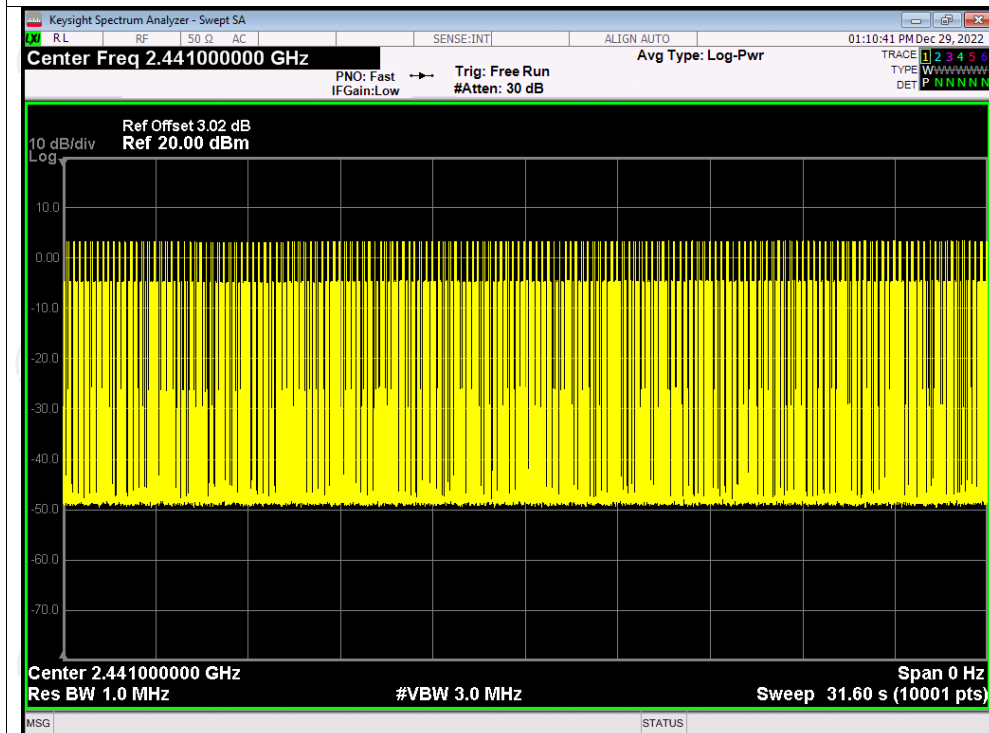
Condition	Mode	Frequency (MHz)	Pulse Time (ms)	Total Dwell Time (ms)	Burst Count	Period Time (ms)	Limit (ms)	Verdict
NVNT	1-DH1	2441	0.41	130.38	318	31600	400	Pass
NVNT	1-DH3	2441	1.66	267.26	161	31600	400	Pass
NVNT	1-DH5	2441	2.91	355.02	122	31600	400	Pass
NVNT	2-DH1	2441	0.40	200.40	501	31600	400	Pass
NVNT	2-DH3	2441	1.65	267.30	162	31600	400	Pass
NVNT	2-DH5	2441	2.90	301.60	104	31600	400	Pass
NVNT	3-DH1	2441	0.40	127.60	319	31600	400	Pass
NVNT	3-DH3	2441	1.65	310.20	188	31600	400	Pass
NVNT	3-DH5	2441	2.90	330.60	114	31600	400	Pass

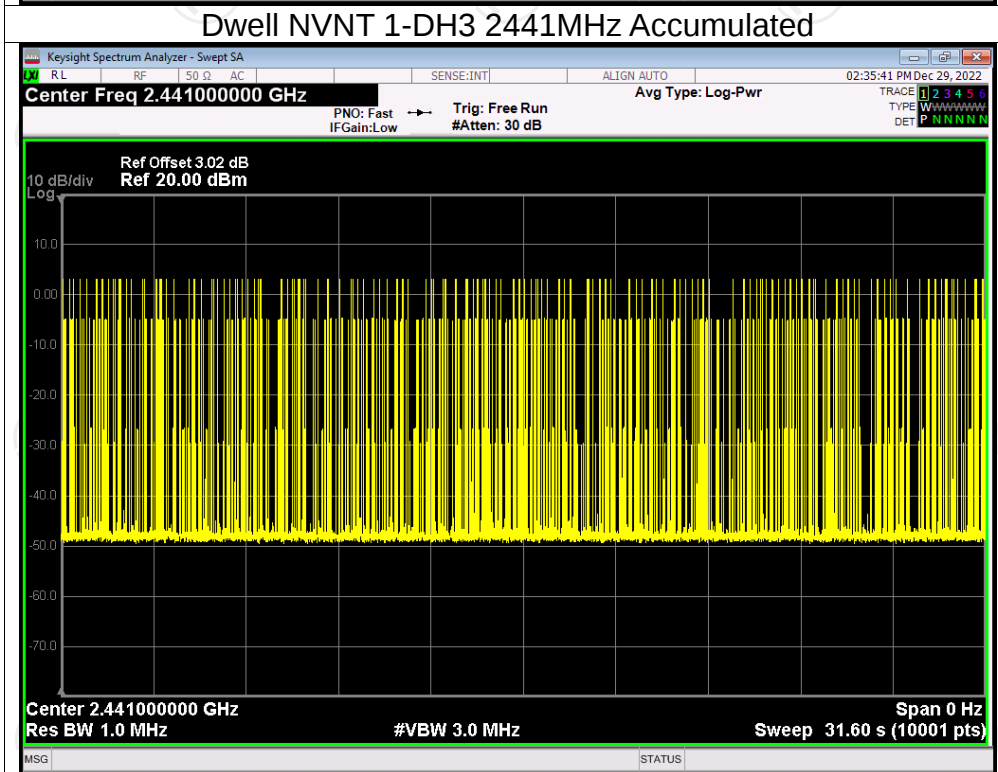
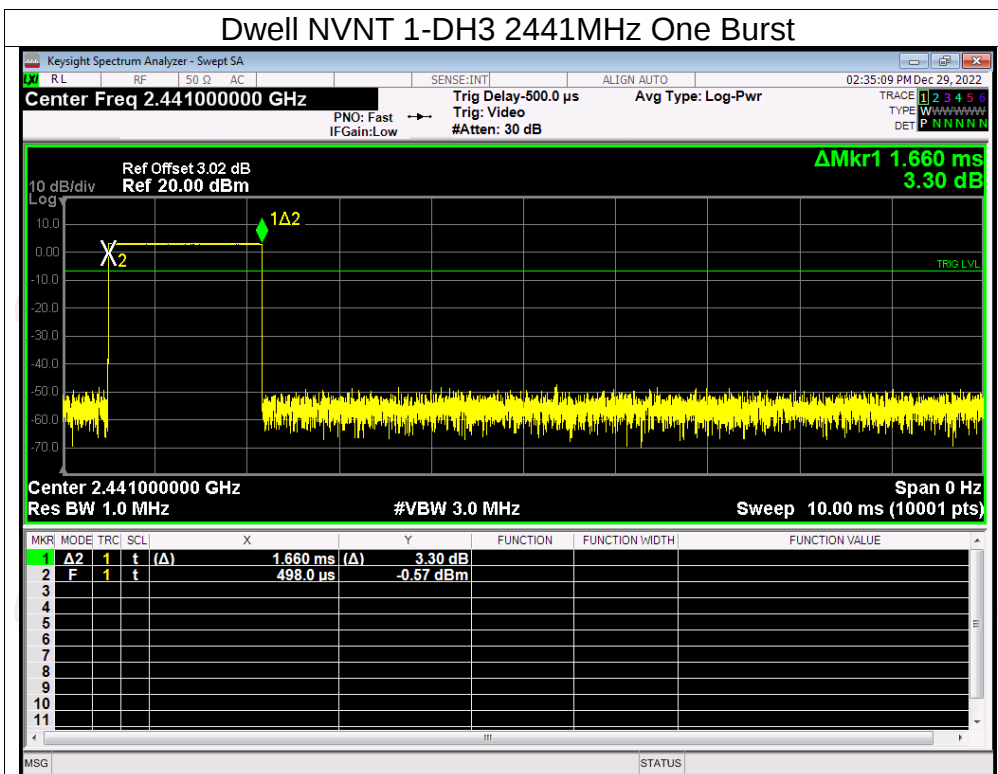
Test Graphs

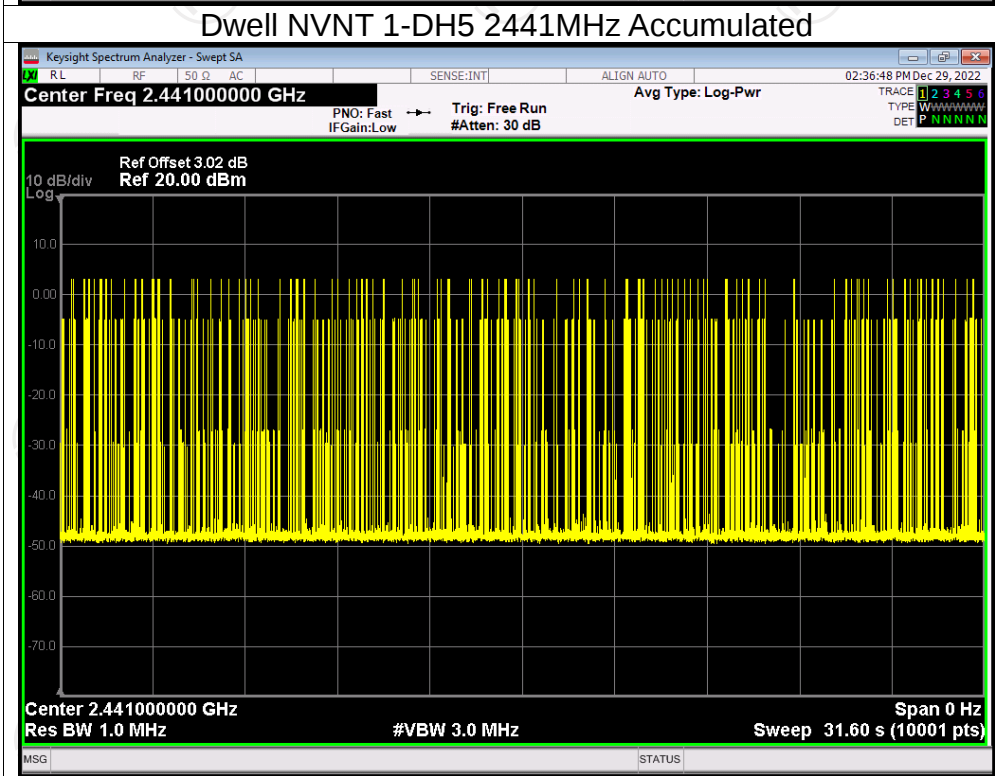
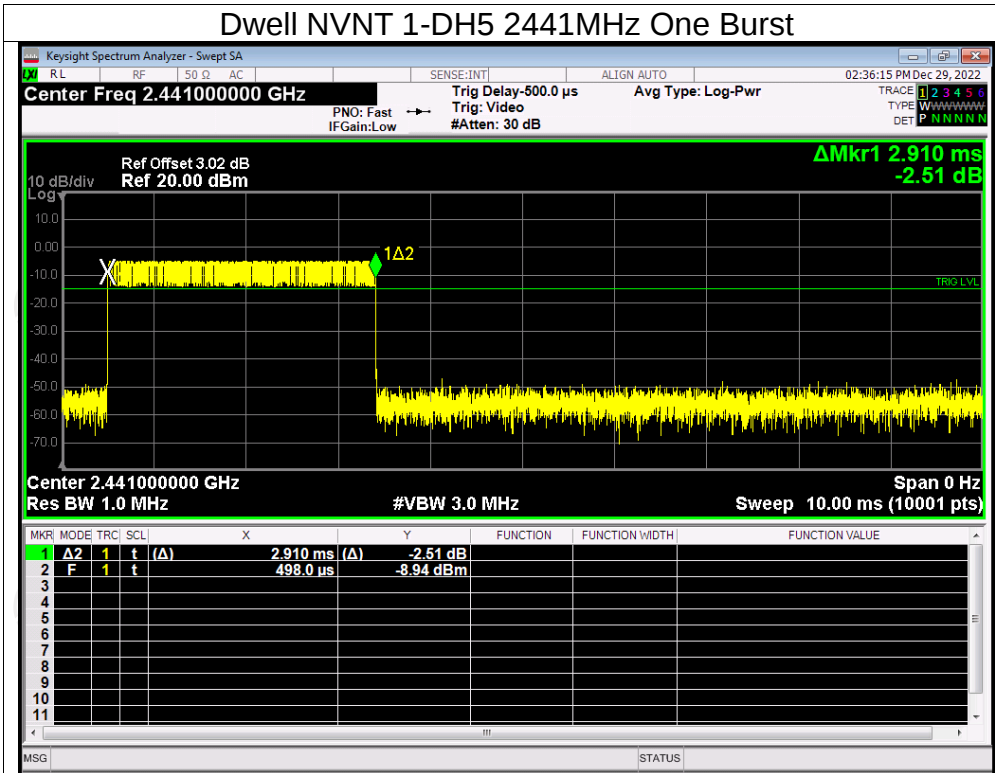
Dwell NVNT 1-DH1 2441MHz One Burst



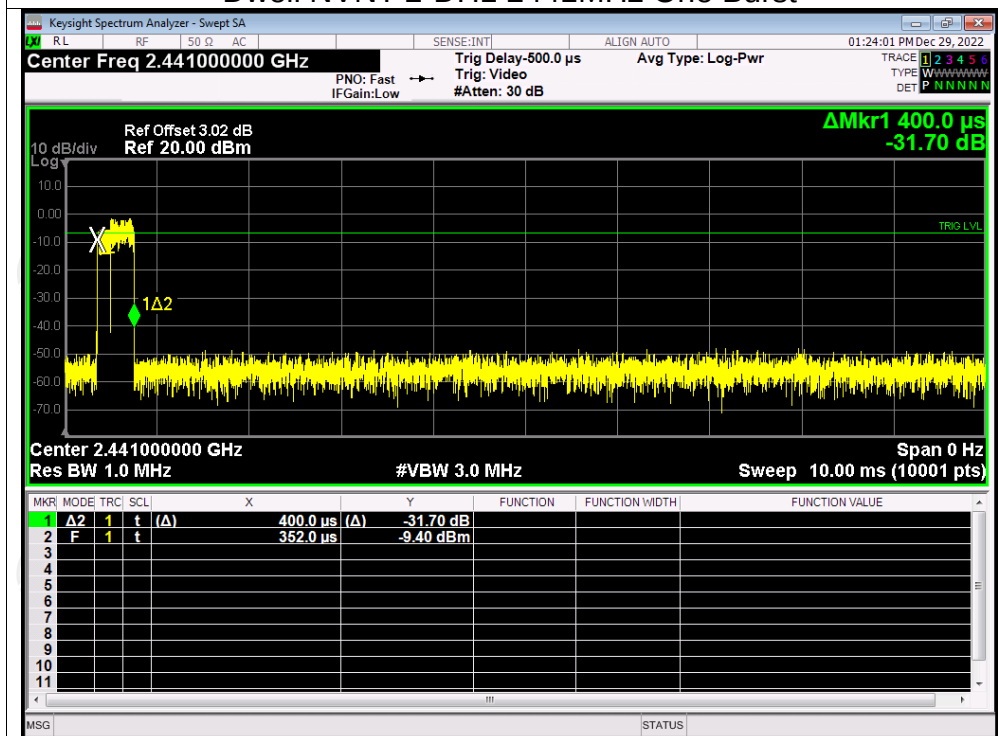
Dwell NVNT 1-DH1 2441MHz Accumulated



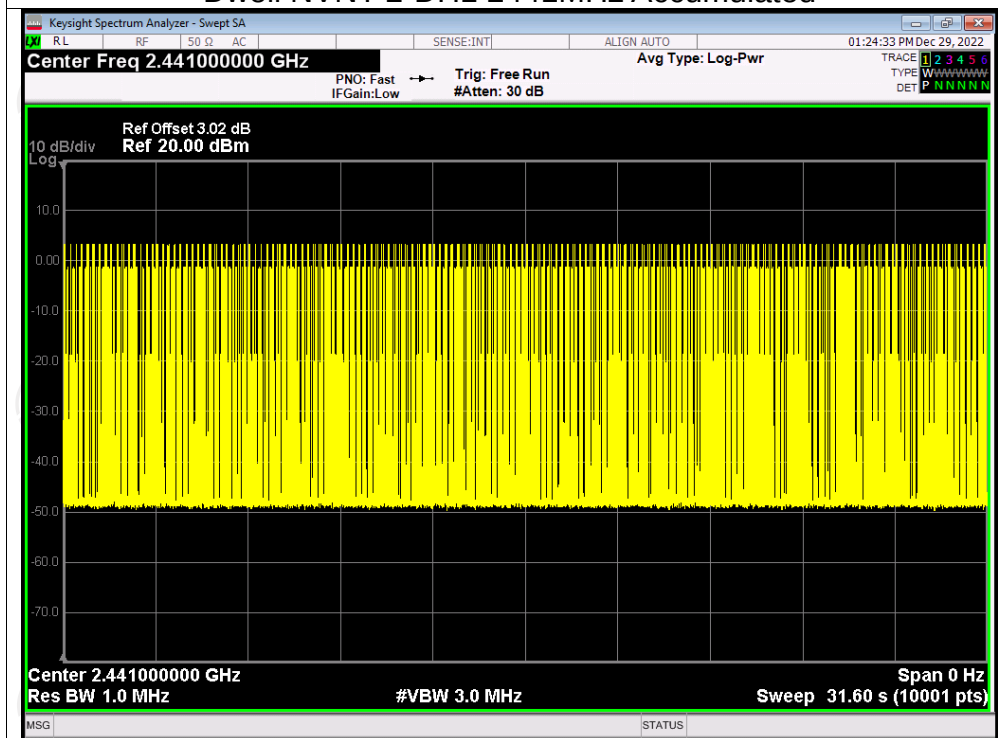


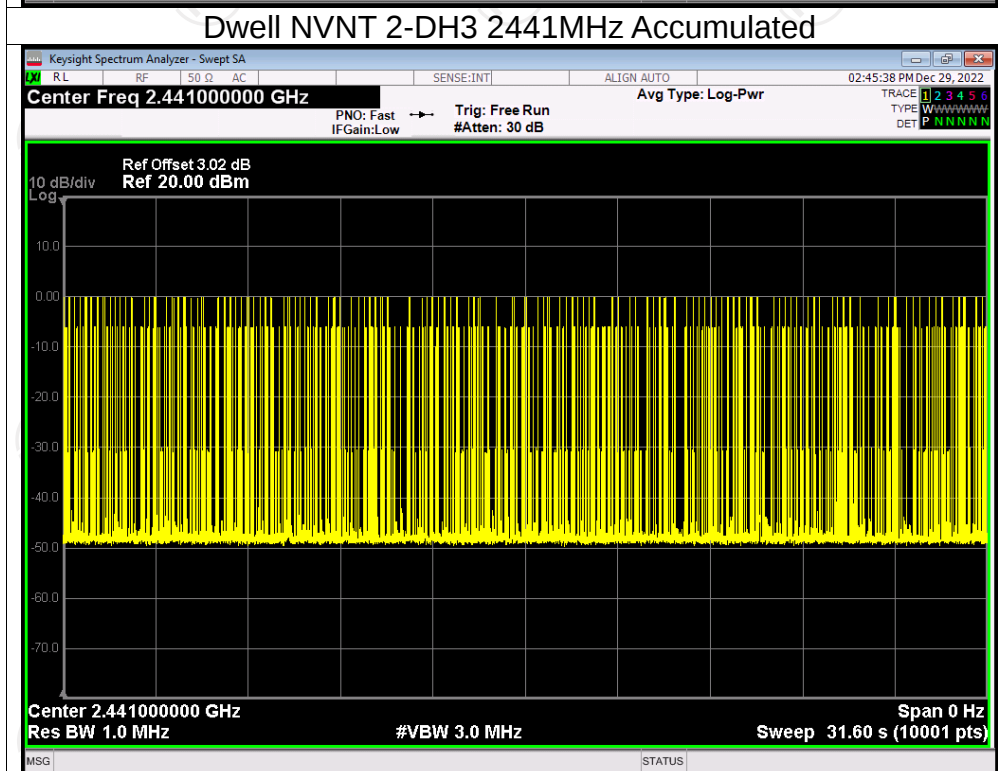
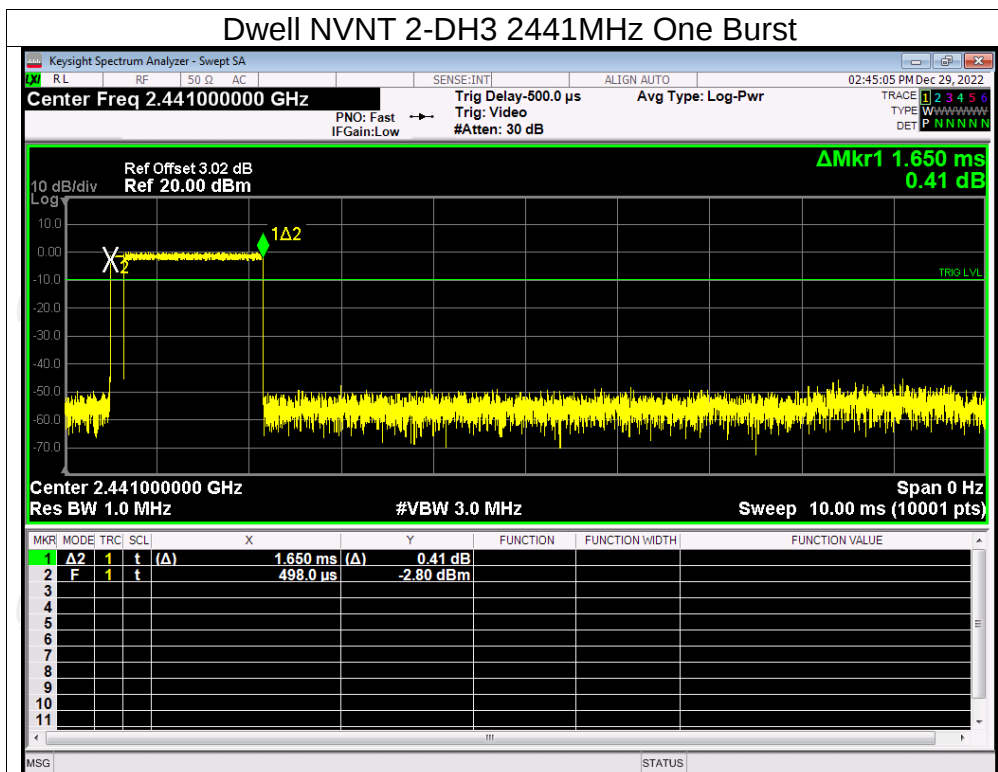


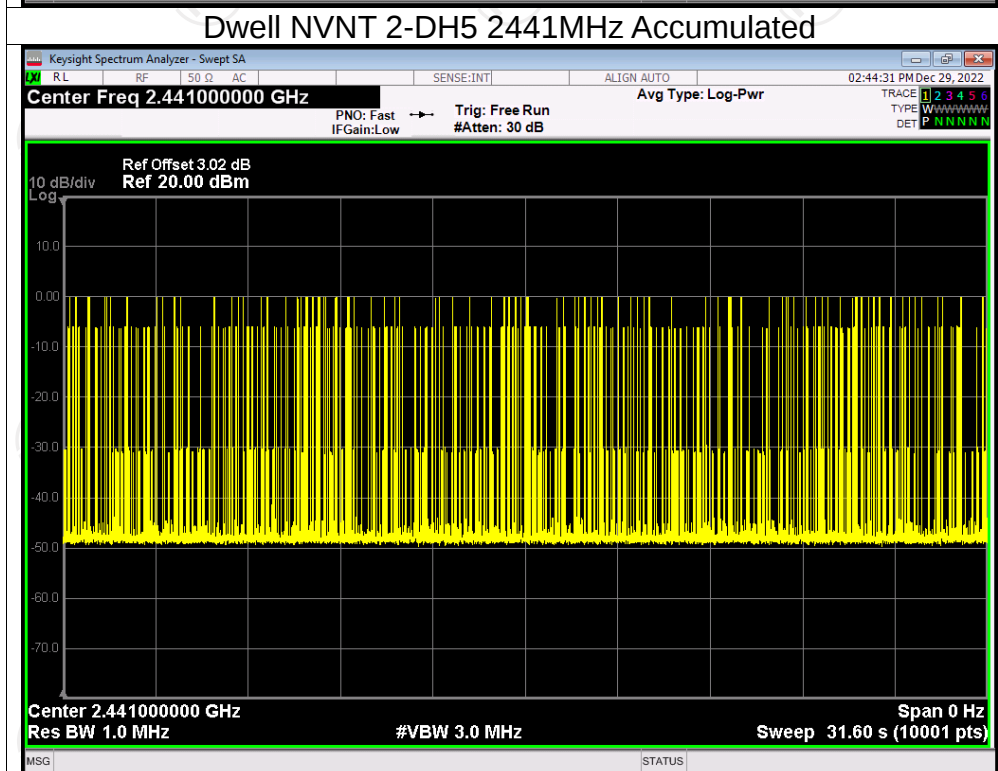
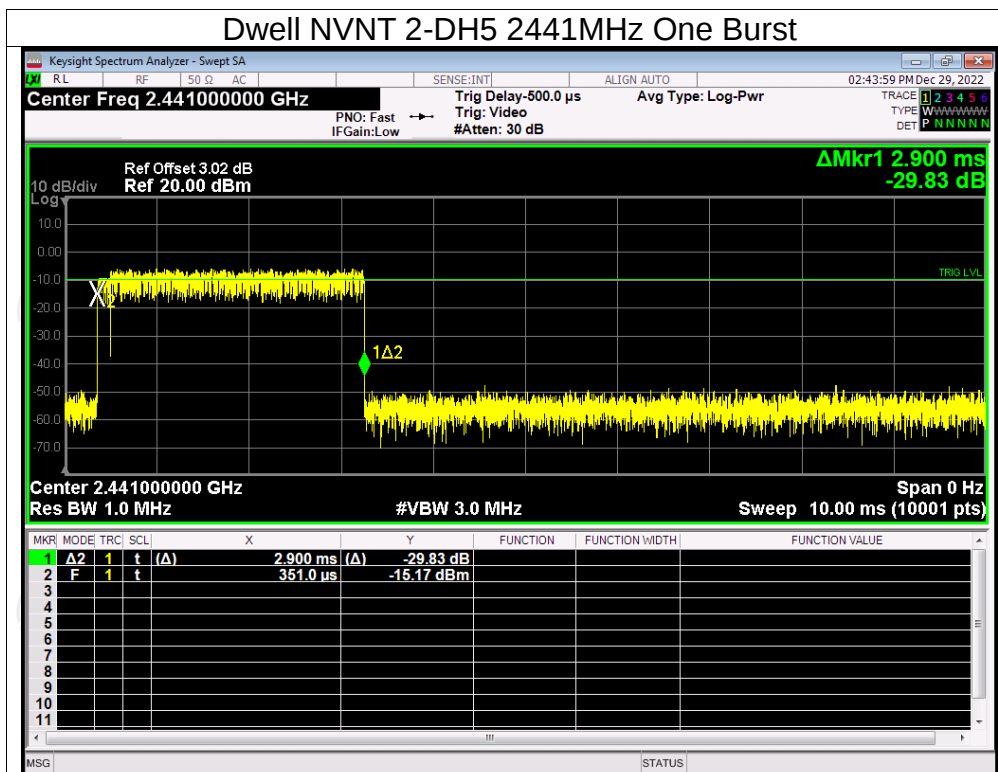
Dwell NVNT 2-DH1 2441MHz One Burst

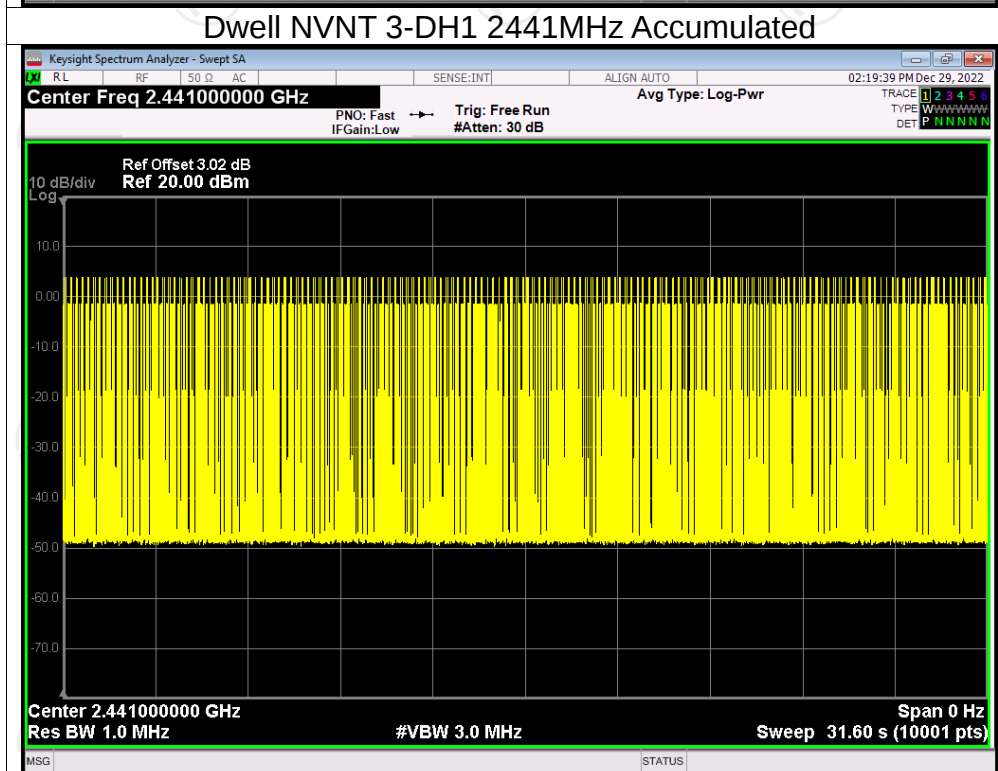
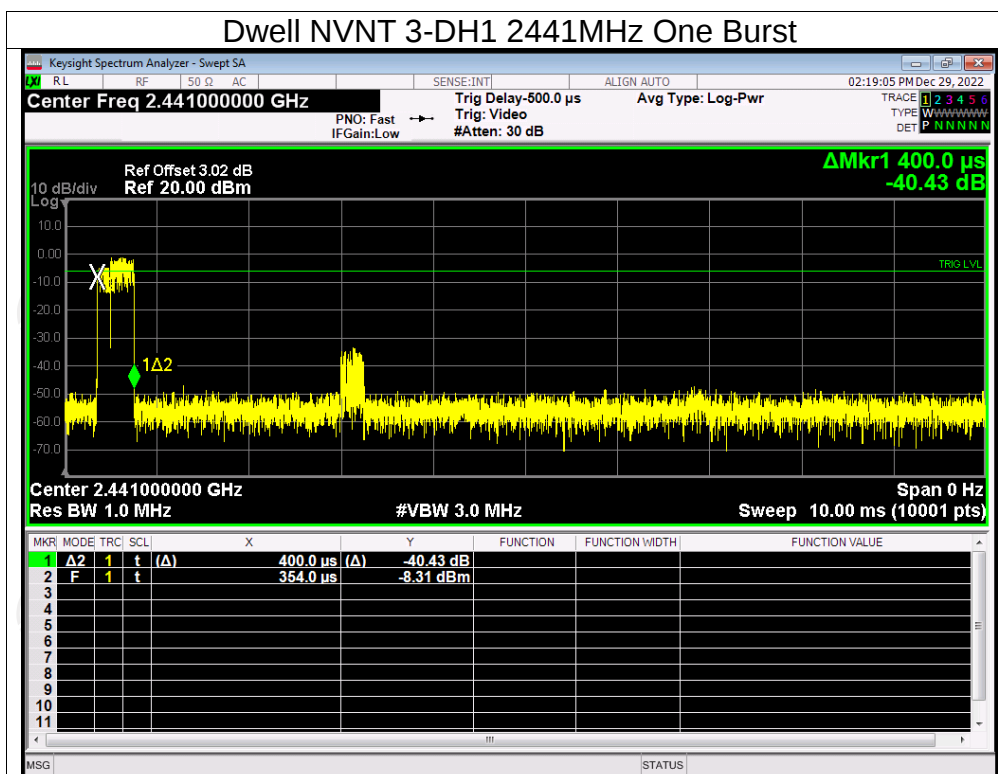


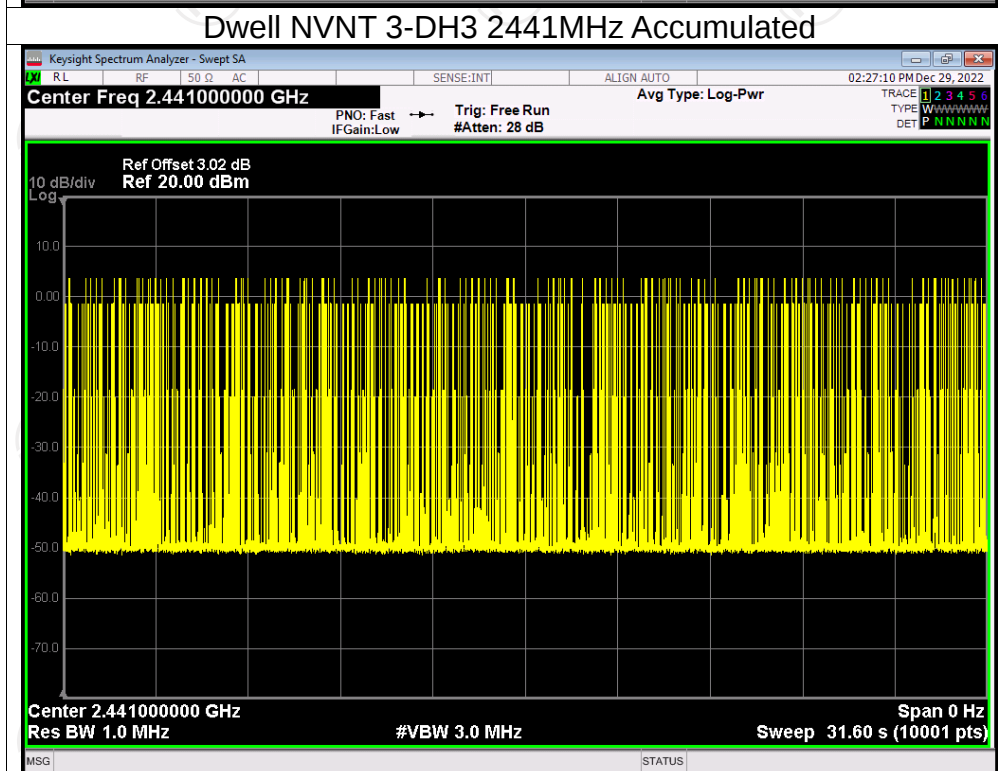
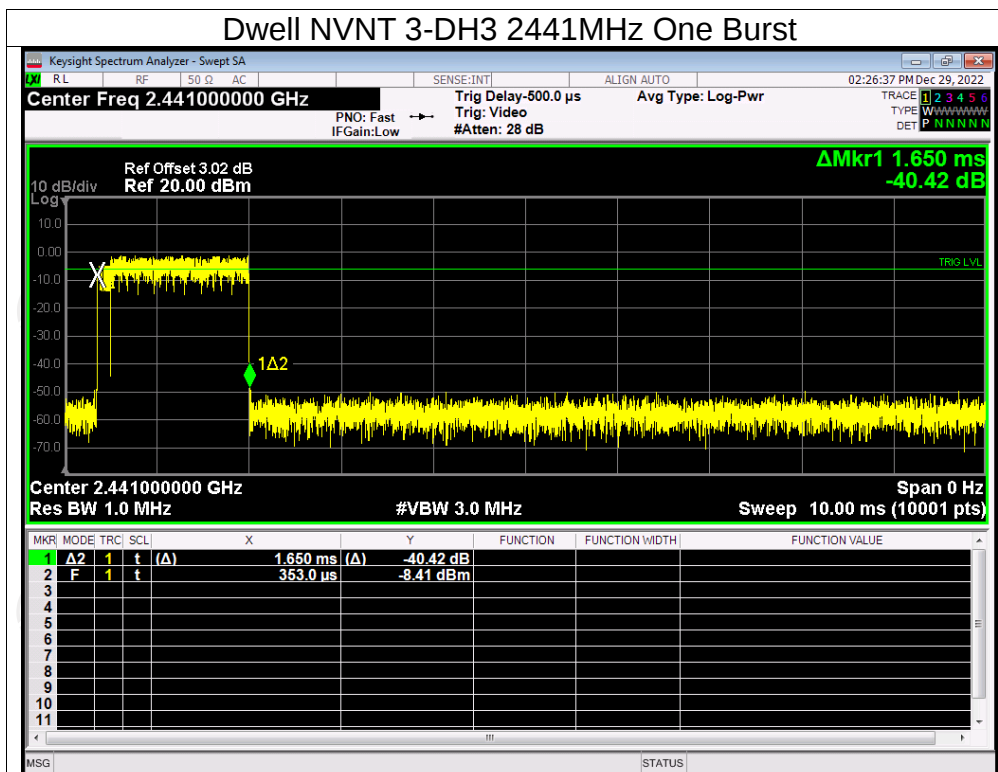
Dwell NVNT 2-DH1 2441MHz Accumulated

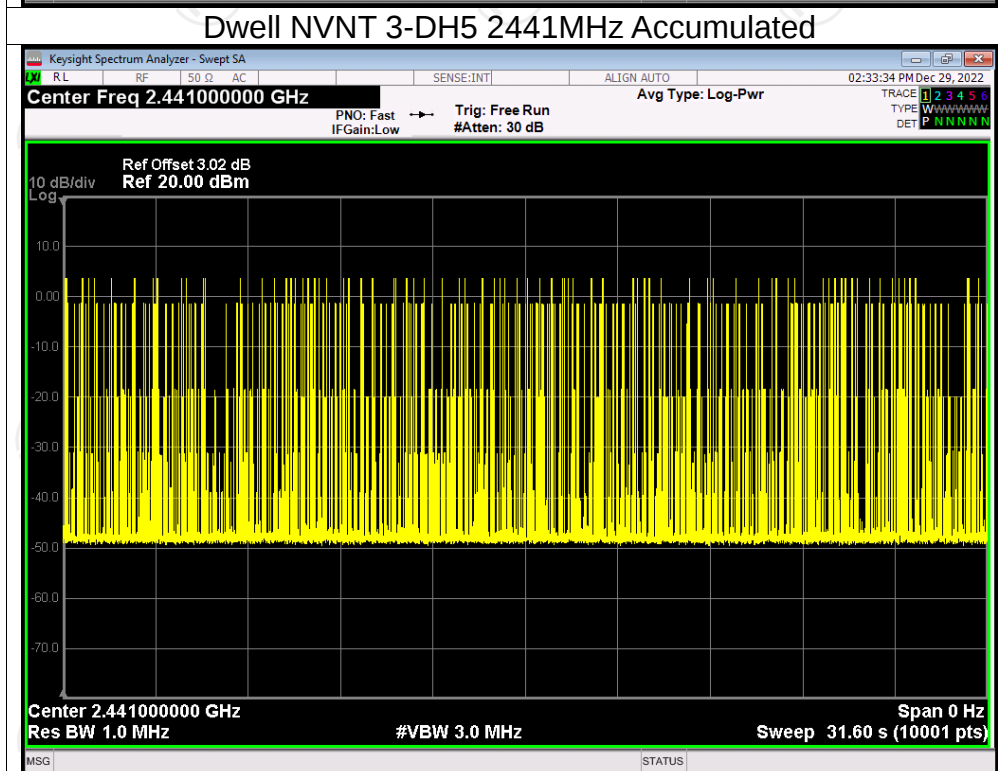
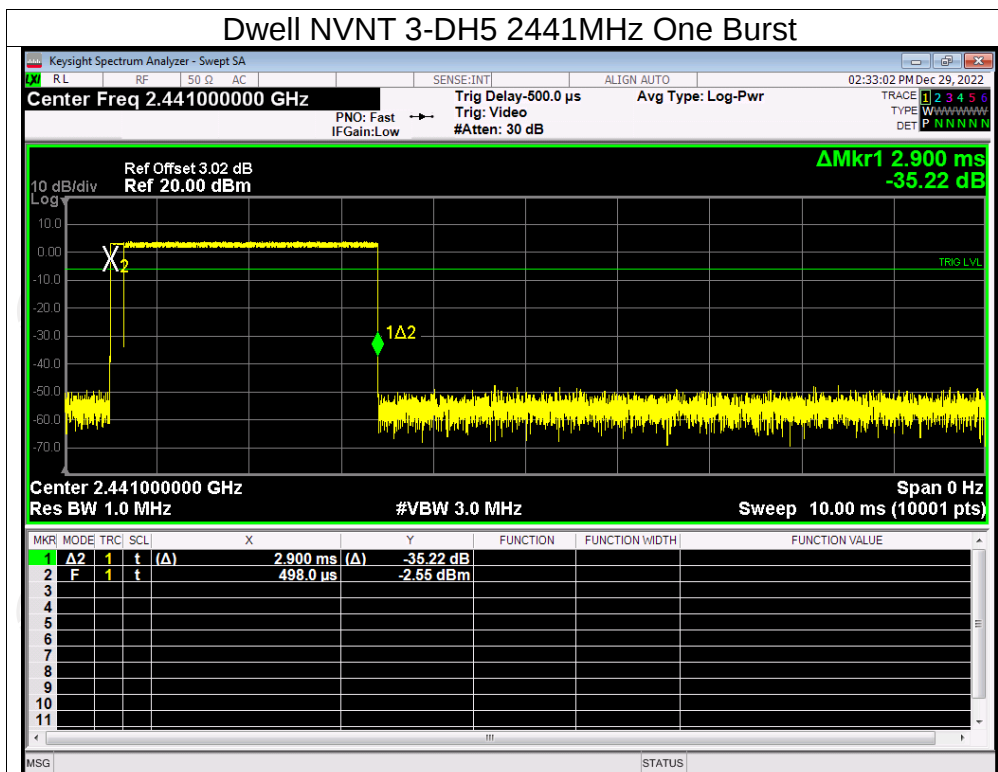










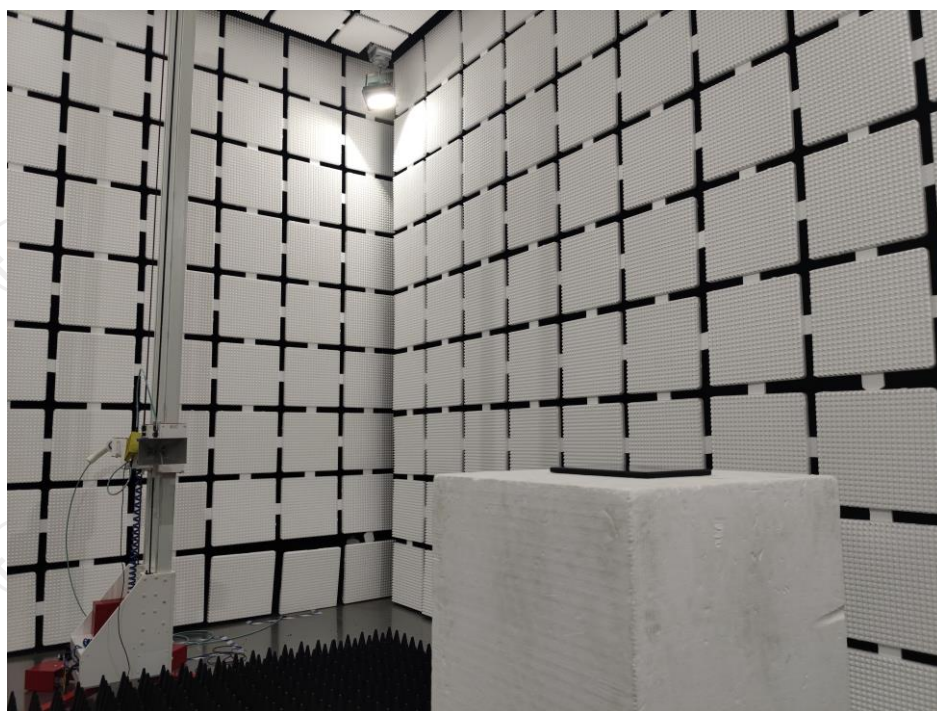
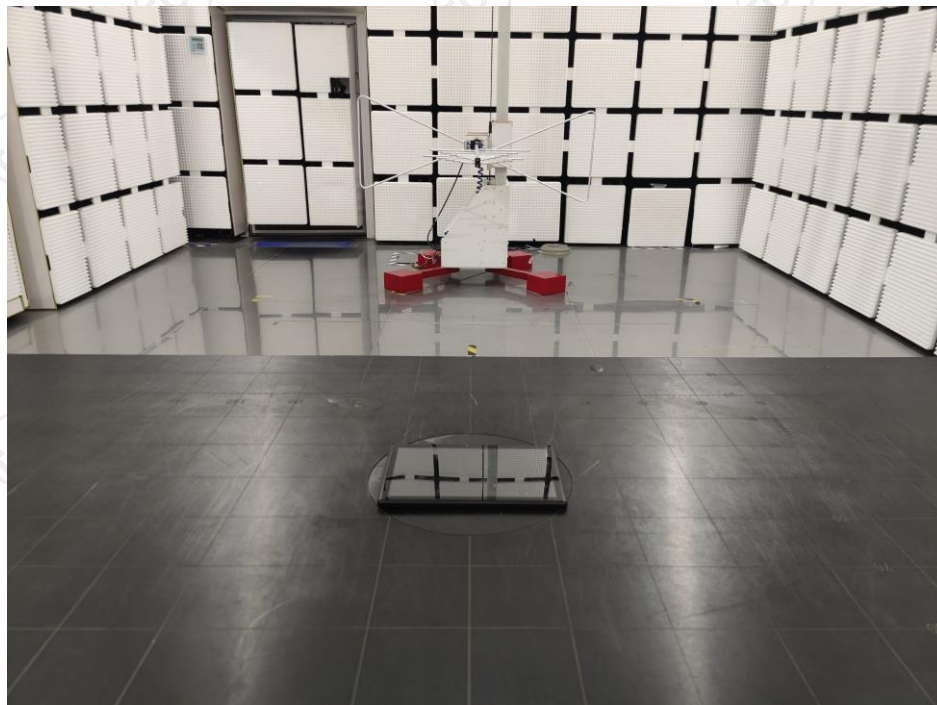


Appendix B: Photographs of Test Setup

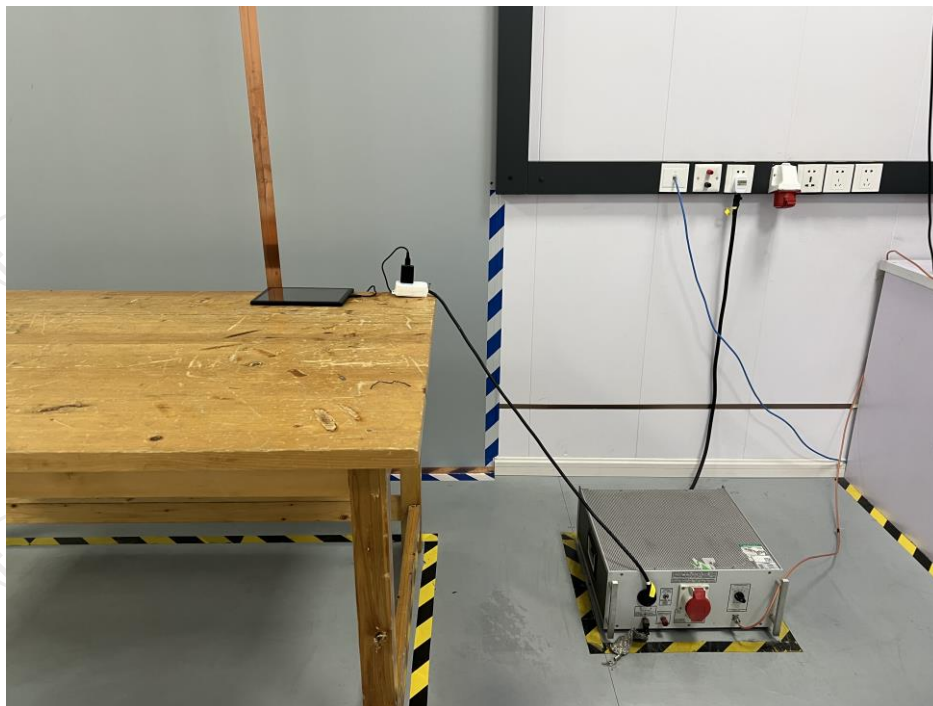
Product: LTE Tablet

Model: X10 ULTRA

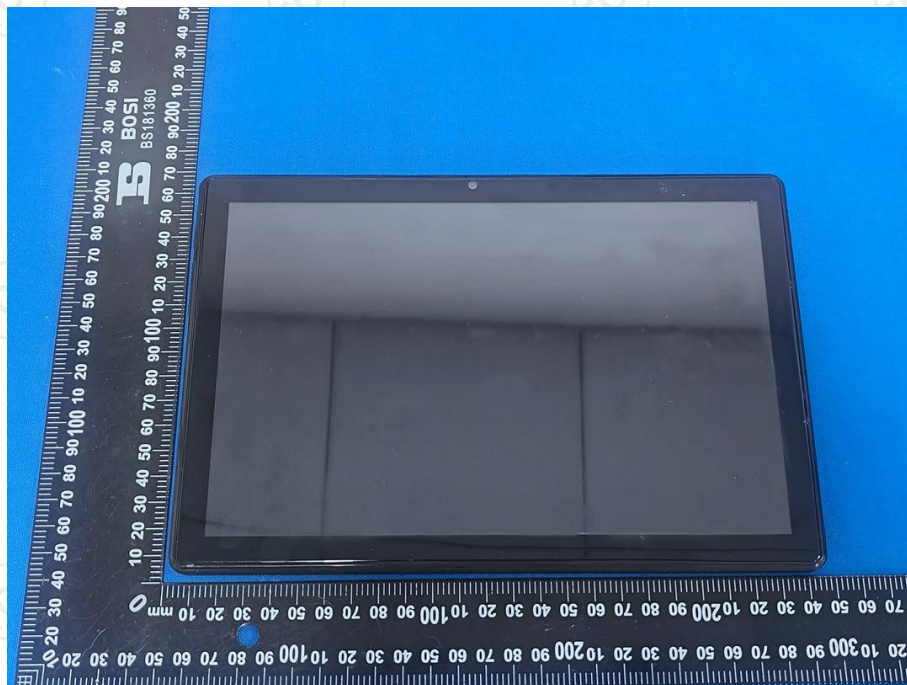
Radiated Emission



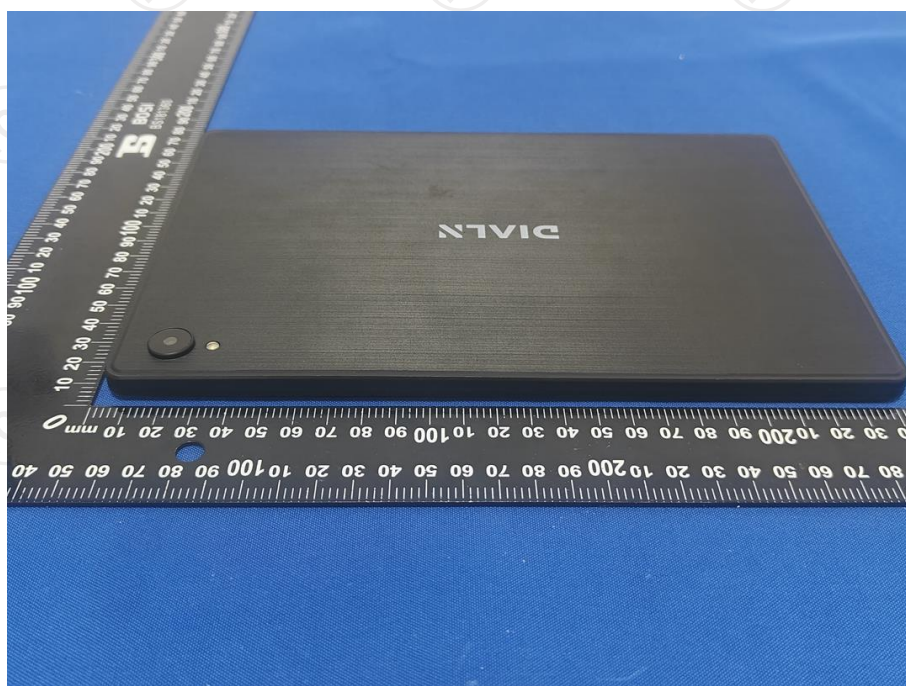
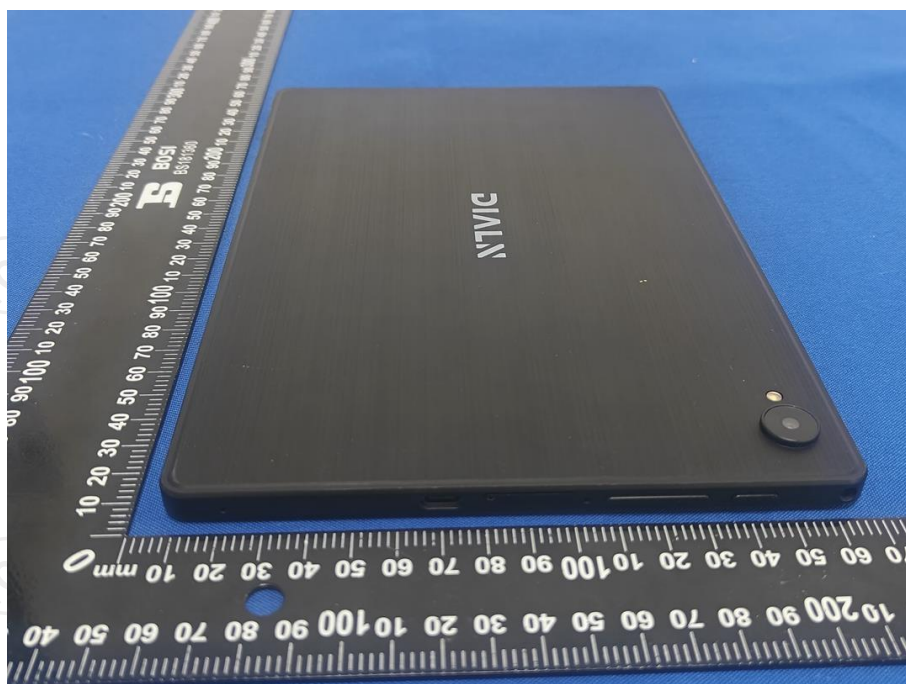
Conducted Emission

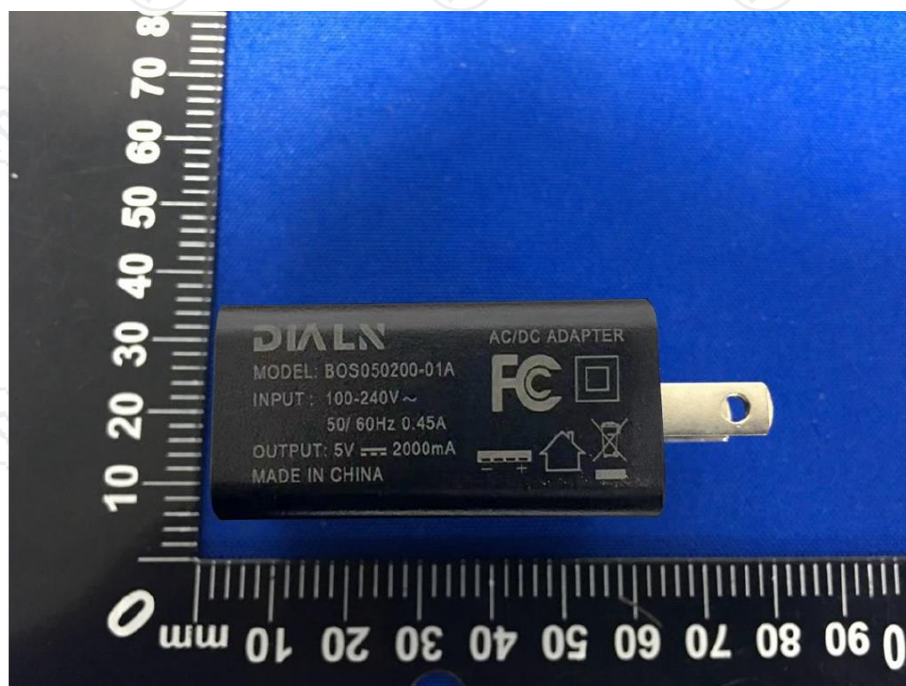
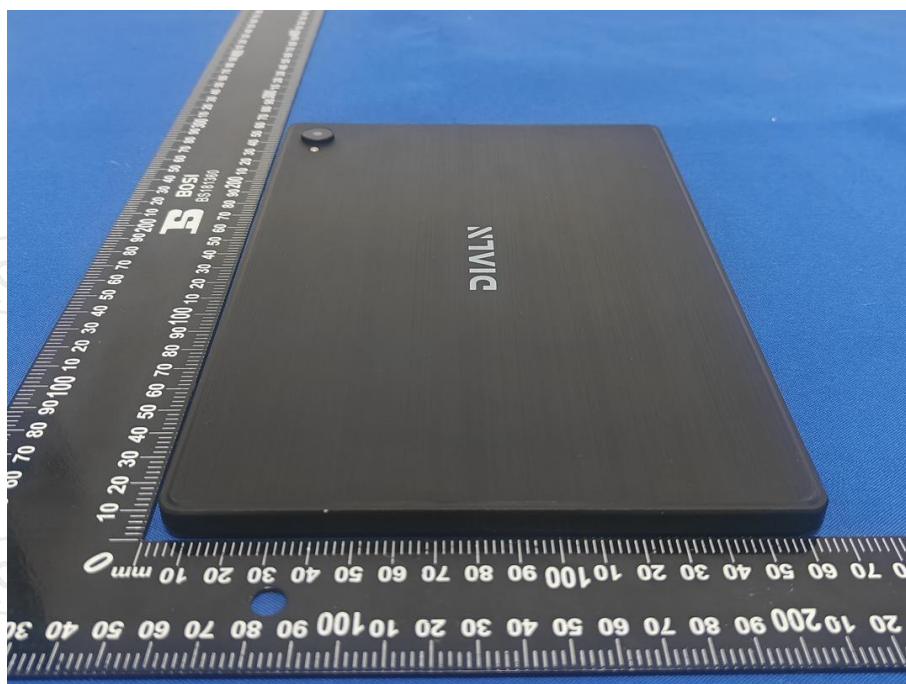


Appendix C: Photographs of EUT
Product: LTE Tablet
Model: X10 ULTRA
External Photos

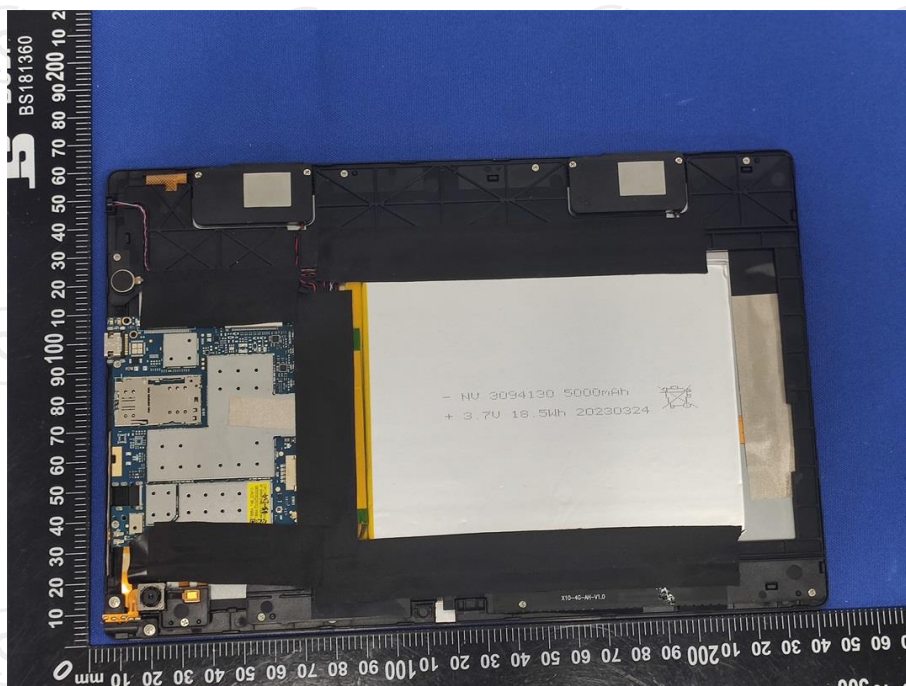
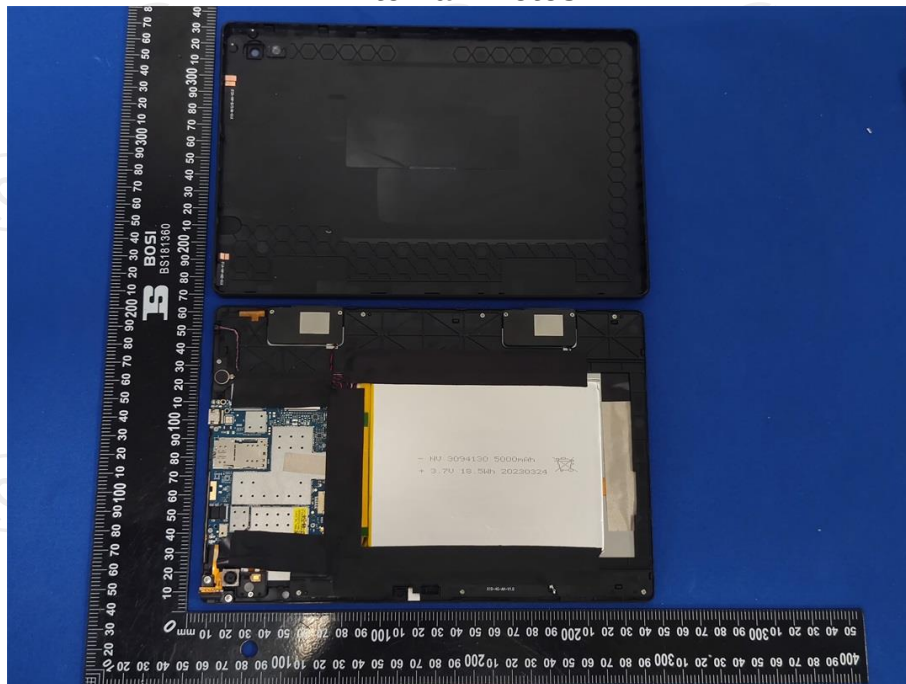


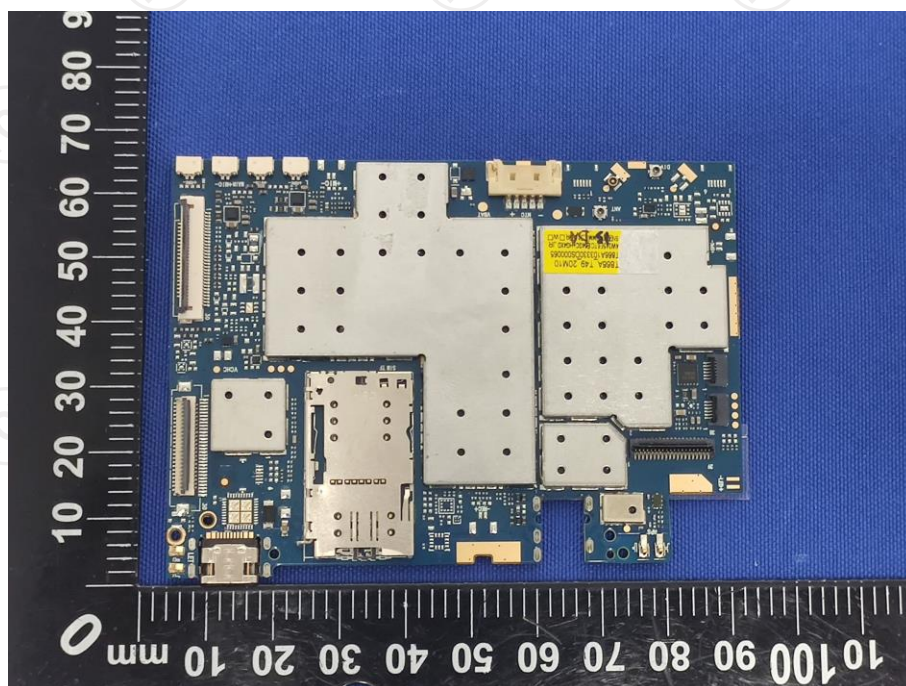
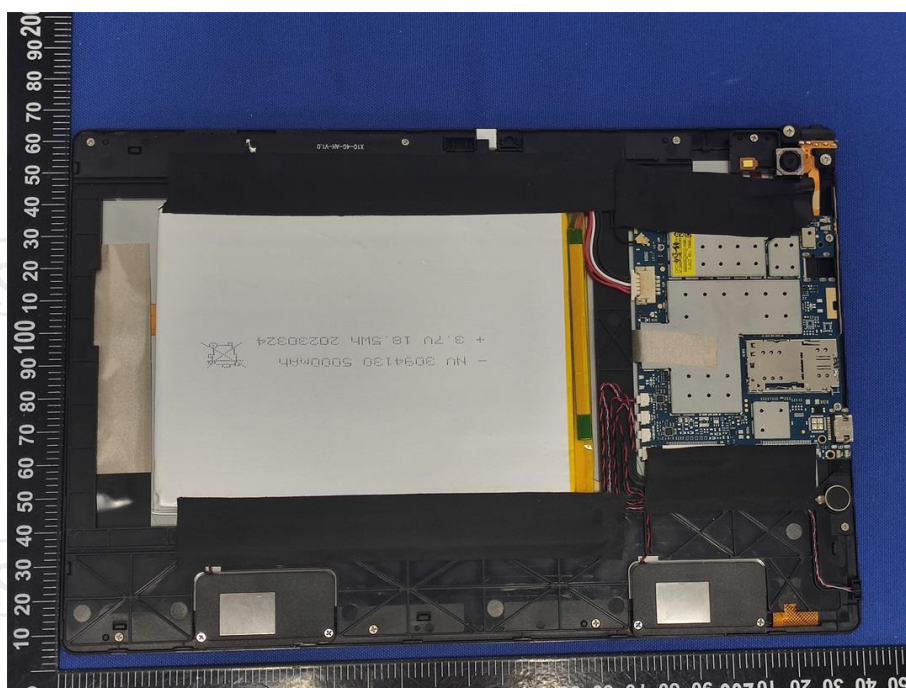


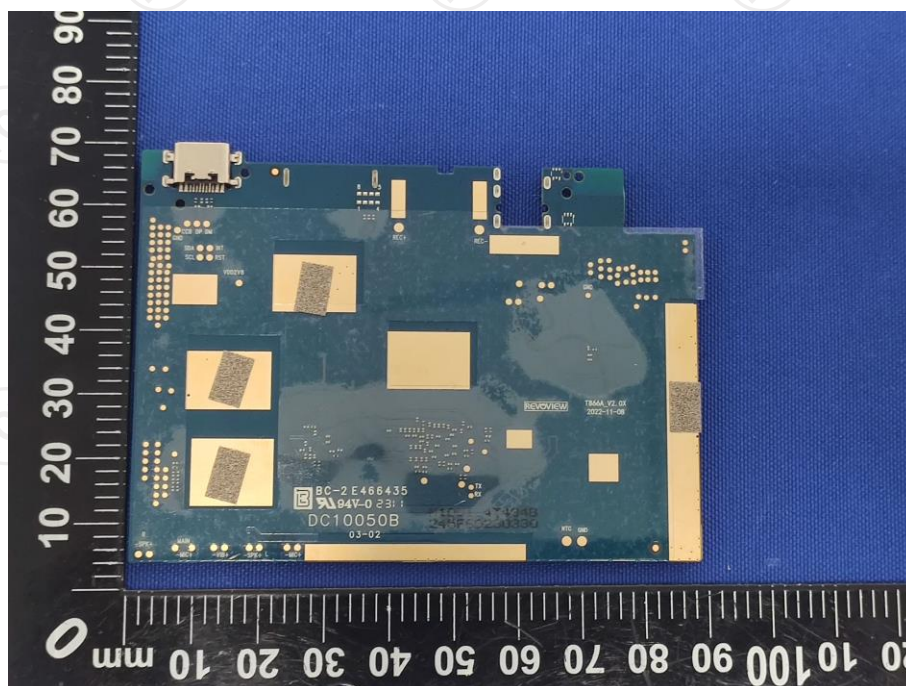
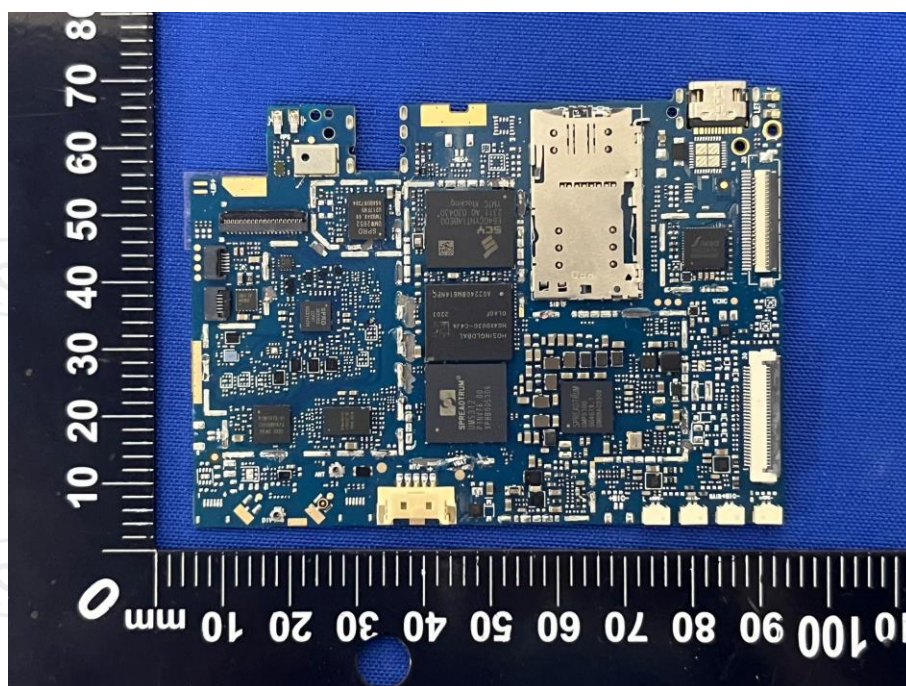


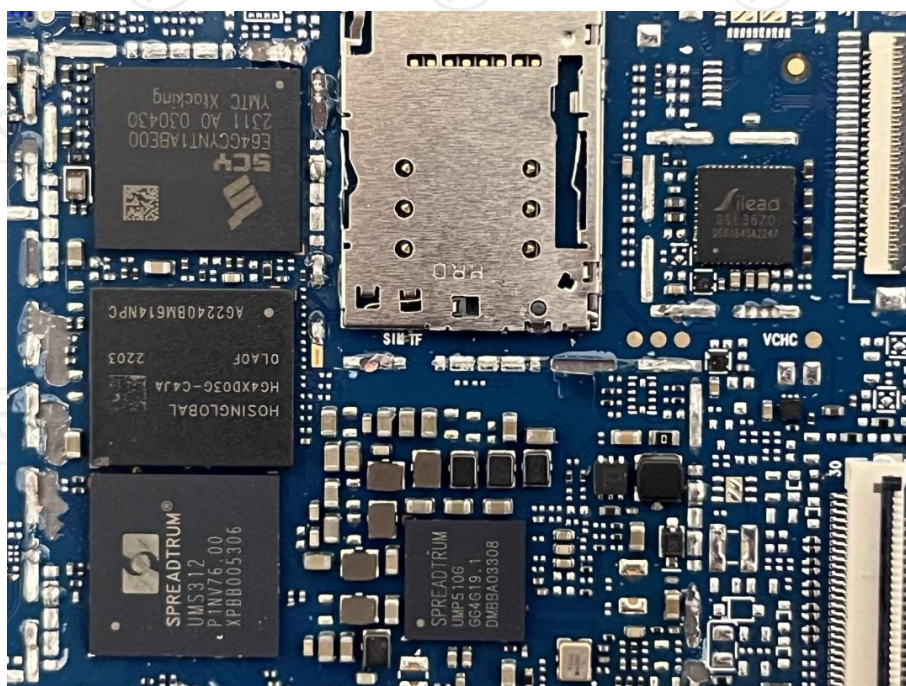
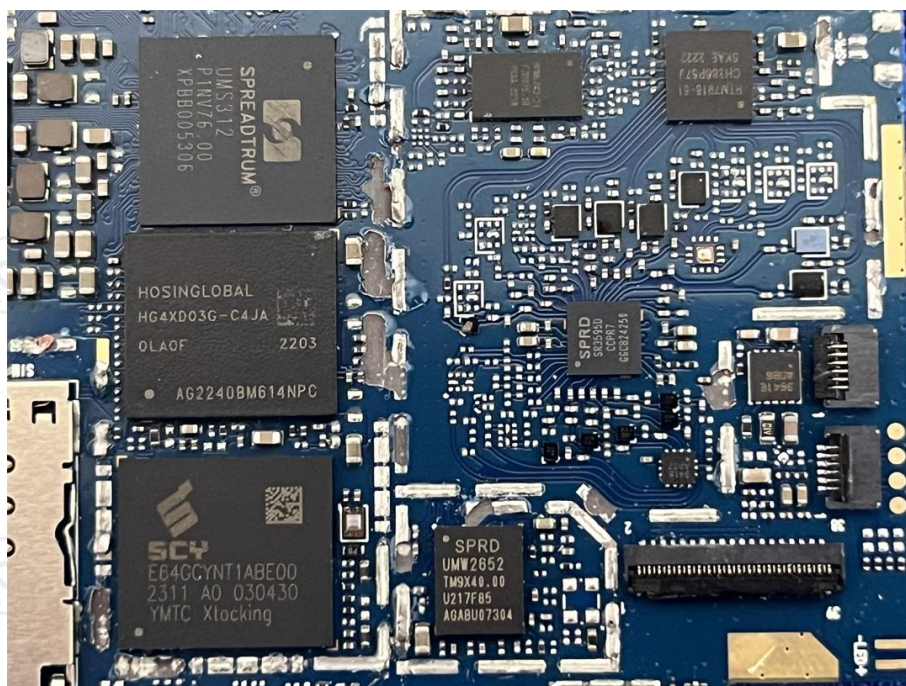


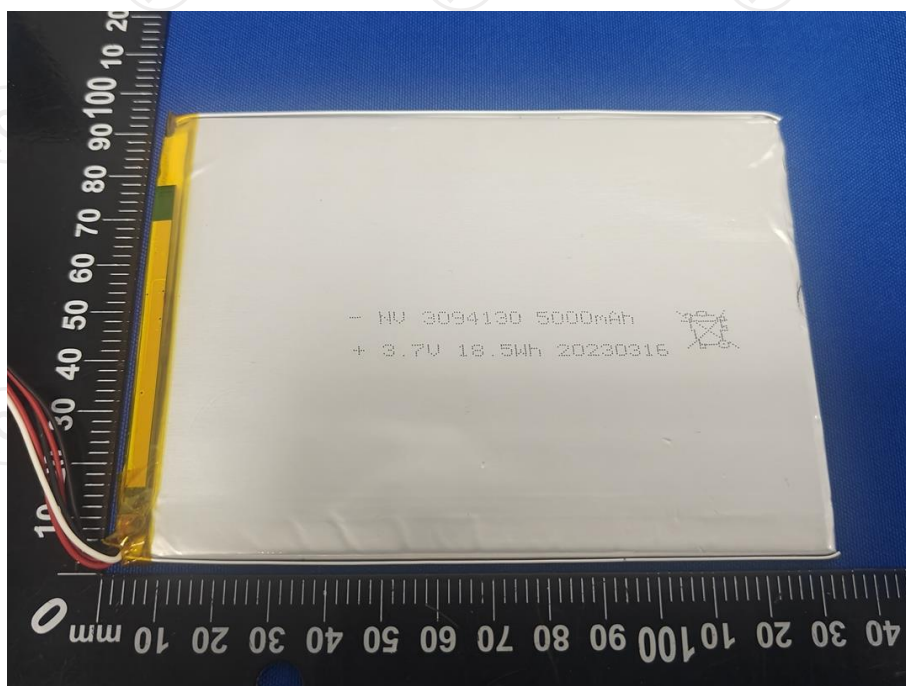
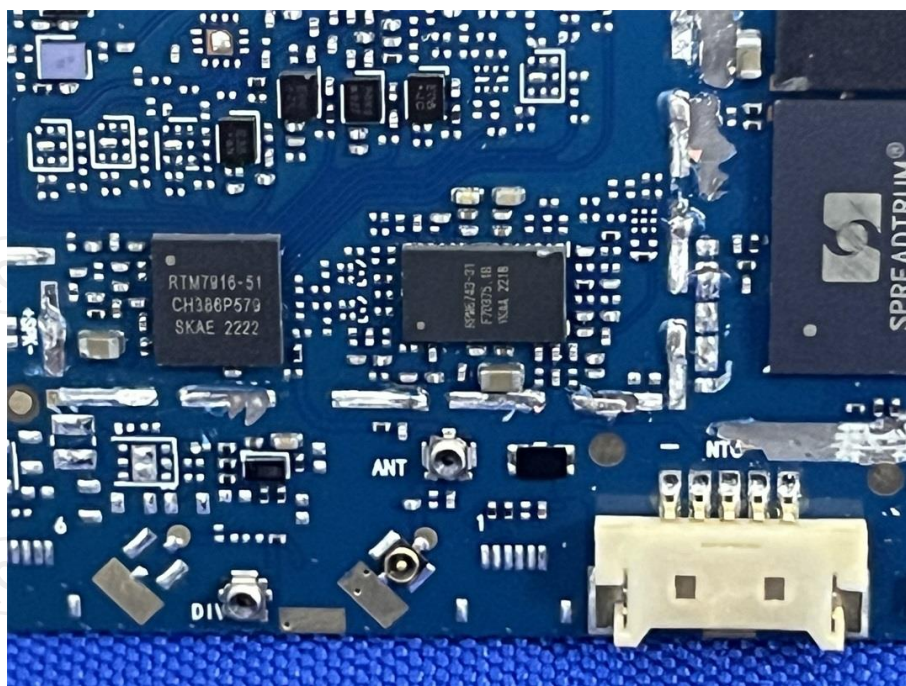
Product: LTE Tablet
Model: X10 ULTRA
Internal Photos

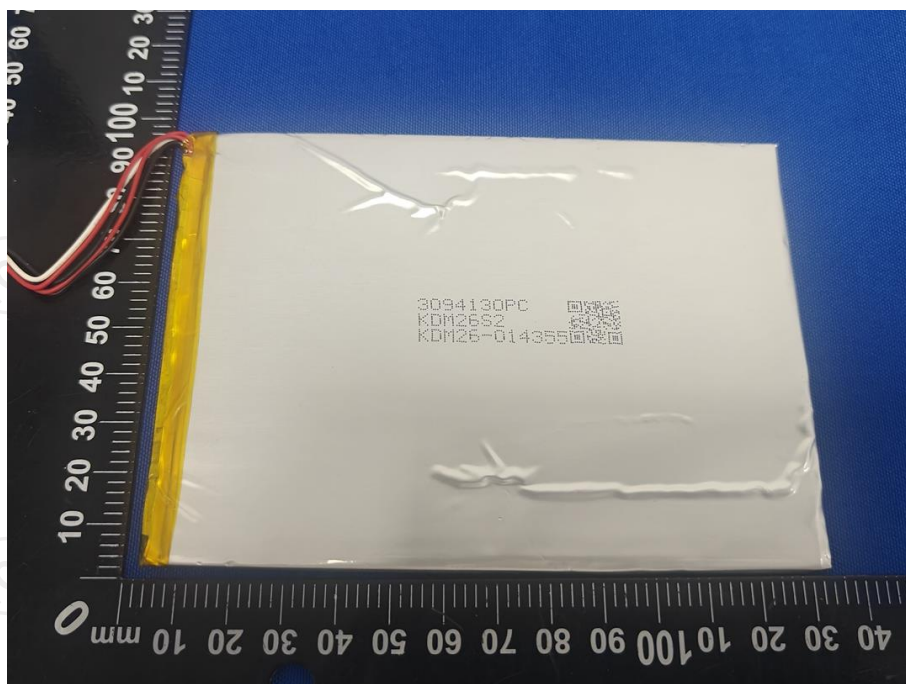












*******END OF REPORT*******